

**Notice of References Cited**Application/Control No.  
09/560,268Applicant(s)/Patent Under  
Reexamination  
LEE ET AL.Examiner  
DuyVu n DeoArt Unit  
1765

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
	A	US-5,919,311	07-1999	Shive et al.	134	1
	B	US-5,454,901	10-1995	Tsuji	134	1
	C	US-4,316,765	02-1982	Thiel	156	626
	D	US-5,780,363	07-1998	Delehanty et al.	438	748
	E	US-5,486,266	01-1996	Tsai et al.	134	3
	F	US-5,858,861	01-1999	Weng et al.	438	750
	G	US-				
	H	US-				
	I	US-				
	J	US-				
	K	US-				
	L	US-				
	M	US-				

**FOREIGN PATENT DOCUMENTS**

*		Document Number	Date	Country	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY				
	N						
	O						
	P						
	Q						
	R						
	S						
	T						

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.